TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

## TC74ACT374P,TC74ACT374F,TC74ACT374FT

#### Octal D-Type Flip-Flop with 3-State Output

The TC74ACT374 is an advanced high speed CMOS OCTAL FLIP-FLOP fabricated with silicon gate and double-layer metal wiring C<sup>2</sup>MOS technology.

It achieves the high speed operation similar to equivalent Bipolar Schottky TTL while maintaining the CMOS low power dissipation.

This devices may be used as a level converter for interfacing TTL or NMOS to High Speed CMOS. The inputs are compatible with TTL, NMOS and CMOS output voltage levels.

These 8-bit D-type flip-flops are controlled by a clock input (CK) and a output enable input  $(\overline{OE})$ .

When the  $\overline{OE}$  input is high, the eight outputs are in a high impedance state.

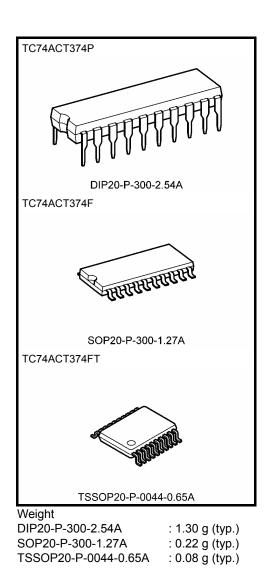
All inputs are equipped with protection circuits against static discharge or transient excess voltage.

#### Features

- High speed:  $f_{max} = 180 \text{ MHz}$  (typ.) at  $V_{CC} = 5 \text{ V}$
- Low power dissipation:  $I_{CC} = 8 \mu A \pmod{at Ta} = 25^{\circ}C$
- Compatible with TTL outputs: VIL = 0.8 V (max)

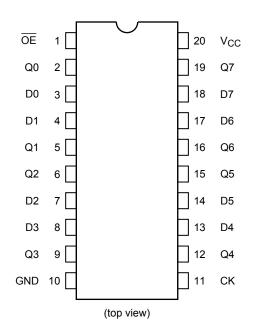
 $V_{IH} = 2.0 V (min)$ 

- Symmetrical output impedance:  $|I_{OH}| = I_{OL} = 24 \text{ mA} (\text{min})$ Capability of driving 50  $\Omega$ transmission lines.
- Balanced propagation delays:  $t_{pLH} \simeq t_{pHL}$
- Pin and function compatible with  $74\mathrm{F}374$

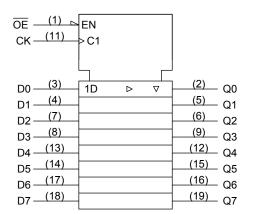


# <u>TOSHIBA</u>

### **Pin Assignment**



### **IEC Logic Symbol**



#### Truth Table

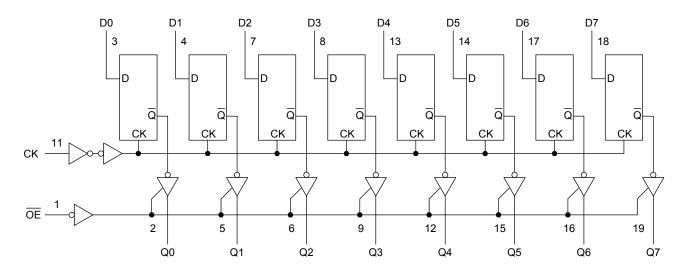
	Inputs	Output				
ŌE	CK D		Q			
Н	Х	Х	Z			
L		Х	Qn			
L		L	L			
L		Н	Н			

X: Don't care

Z: High impedance

Qn: No change

### System Diagram



#### Absolute Maximum Ratings (Note 1)

Characteristics	Symbol	Rating	Unit
Supply voltage range	V <sub>CC</sub>	-0.5 to 7.0	V
DC input voltage	VIN	-0.5 to V <sub>CC</sub> + 0.5	V
DC output voltage	V <sub>OUT</sub>	-0.5 to V <sub>CC</sub> + 0.5	V
Input diode current	I <sub>IK</sub>	±20	mA
Output diode current	IOK	±50	mA
DC output current	IOUT	±50	mA
DC V <sub>CC</sub> /ground current	ICC	±200	mA
Power dissipation	PD	500 (DIP) (Note 2)/180 (SOP/TSSOP)	mW
Storage temperature	T <sub>stg</sub>	−65 to 150	°C

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2: 500 mW in the range of Ta = -40 to  $65^{\circ}$ C. From Ta = 65 to  $85^{\circ}$ C a derating factor of -10 mW/°C should be applied up to 300 mW.

Characteristics	Symbol	Rating	Unit
Supply voltage	V <sub>CC</sub>	4.5 to 5.5	V
Input voltage	V <sub>IN</sub>	0 to V <sub>CC</sub>	V
Output voltage	V <sub>OUT</sub>	0 to V <sub>CC</sub>	V
Operating temperature	T <sub>opr</sub>	-40 to 85	°C
Input rise and fall time	dt/dV	0 to 10	ns/V

#### **Operating Ranges (Note)**

Note: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either VCC or GND.

### **Electrical Characteristics**

#### **DC Characteristics**

Characteristics	Symbol		Test Condition		Ta = 25°C			Ta = −40 to 85°C		Unit	
Grandotonolog				V <sub>CC</sub> (V)	Min	Тур.	Max	Min	Max	Ont	
High-level input voltage	VIH	_			4.5 to 5.5	2.0	_	_	2.0	_	V
Low-level input voltage	V <sub>IL</sub>	_		4.5 to 5.5	_	_	0.8	-	0.8	V	
	V <sub>OH</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OH</sub> = -50 μA		4.5	4.4	4.5	_	4.4	_	
High-level output voltage			I <sub>OH</sub> = −24 mA		4.5	3.94	—	—	3.80	—	V
			I <sub>OH</sub> = −75 mA	(Note)	5.5	—	—	—	3.85	—	
	V <sub>OL</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OL</sub> = 50 μA		4.5	_	0.0	0.1	_	0.1	
Low-level output voltage			I <sub>OL</sub> = 24 mA		4.5	—	—	0.36	—	0.44	V
			I <sub>OL</sub> = 75 mA	(Note)	5.5	—	—	—	—	1.65	
3-state output off-state current	I <sub>OZ</sub>	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $V_{OUT} = V_{CC} \text{ or } GND$		5.5	_	—	±0.5		±5.0	μΑ	
Input leakage current	I <sub>IN</sub>	V <sub>IN</sub> = V <sub>CC</sub> or GND		5.5	_	_	±0.1	-	±1.0	μA	
	ICC	$V_{IN} = V_C$	V <sub>IN</sub> = V <sub>CC</sub> or GND		5.5	_	—	8.0	_	80.0	μA
Quiescent supply current	Ι <sub>C</sub>	Per input: V <sub>IN</sub> = 3.4 V Other input: V <sub>CC</sub> or GND		5.5	_	_	1.35	_	1.5	mA	

Note: This spec indicates the capability of driving 50  $\Omega$  transmission lines.

One output should be tested at a time for a 10 ms maximum duration.

#### Timing Requirements (input: $t_r = t_f = 3 \text{ ns}$ )

Characteristics	eristics Symbol Test Cond		ndition			Unit	
			V <sub>CC</sub> (V)	Limit	Limit		
Minimum pulse width	t <sub>w (H)</sub>		5.0 ± 0.5	5.0	5.0	ns	
(CK)	t <sub>w (L)</sub>		5.0 ± 0.5	5.0	0.0	113	
Minimum set-up time	t <sub>s</sub>	—	5.0 ± 0.5	3.0	3.0	ns	
Minimum hold time	t <sub>h</sub>	—	5.0 ± 0.5	2.0	2.0	ns	

#### AC Characteristics (C<sub>L</sub> = 50 pF, R<sub>L</sub> = 500 $\Omega$ , input: t<sub>r</sub> = t<sub>f</sub> = 3 ns)

Characteristics	Symbol	Test Condition		-	Ta = 25°0	2	Ta = −40 to 85°C		Unit
	- ,		V <sub>CC</sub> (V)	Min	Тур.	Max	Min	Max	
Propagation delay time (CK-Q)	t <sub>pLH</sub> t <sub>pHL</sub>	_	5.0 ± 0.5	_	6.1	9.6	1.0	11.0	ns
Output enable time	t <sub>pZL</sub> t <sub>pZH</sub>	_	5.0 ± 0.5	_	6.2	10.1	1.0	11.5	ns
Output disable time	t <sub>pLZ</sub> t <sub>pHZ</sub>	_	5.0 ± 0.5	_	5.6	7.9	1.0	9.0	ns
Maximum clock frequency	f <sub>max</sub>	_	5.0 ± 0.5	95	160	_	95	_	MHz
Input capacitance	C <sub>IN</sub>	_		_	5	10	_	10	pF
Output capacitance	C <sub>OUT</sub>	—		_	10	_	_	—	pF
Power dissipation capacitance	C <sub>PD</sub>		(Note)	_	34	_	_	_	pF

Note: C<sub>PD</sub> is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

 $I_{CC (opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/8 (per F/F)$ 

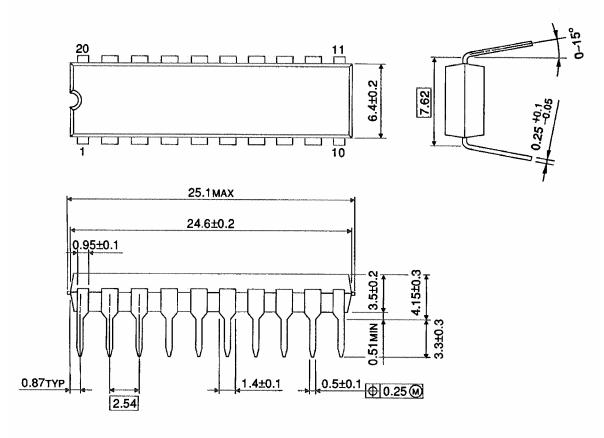
And the total  $C_{PD}$  when n pcs. of F/F operate can be gained by the following equation:

C<sub>PD</sub> (total) = 22 + 12·n

#### **Package Dimensions**

DIP20-P-300-2.54A

Unit : mm



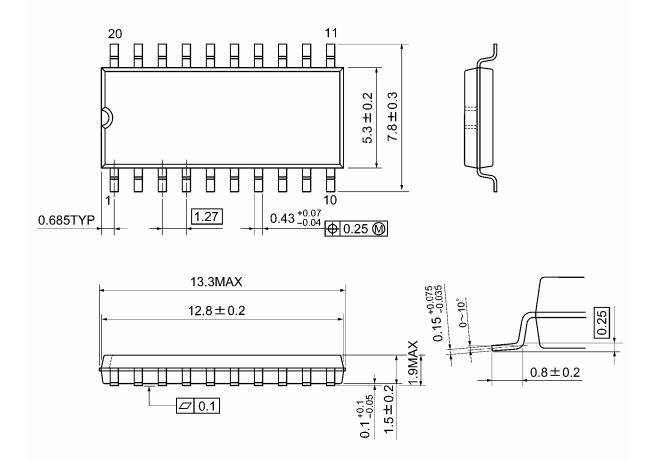
Weight: 1.30 g (typ.)

# **TOSHIBA**

### Package Dimensions

SOP20-P-300-1.27A

Unit: mm



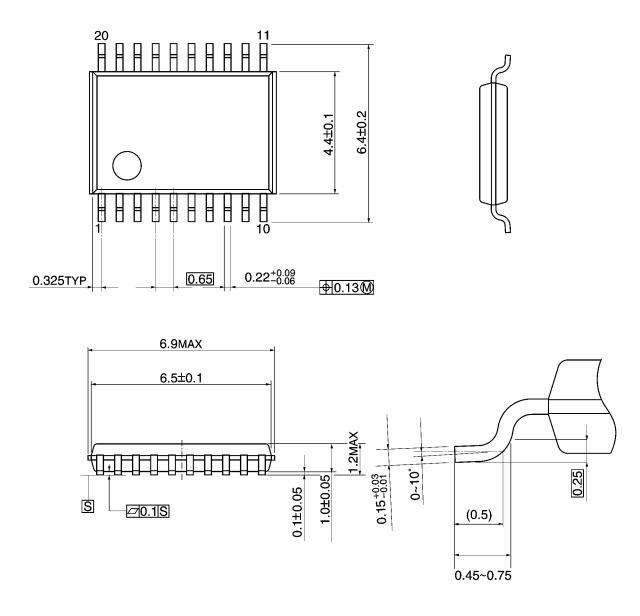
Weight: 0.22 g (typ.)

# **TOSHIBA**

## Package Dimensions

TSSOP20-P-0044-0.65A

Unit: mm



Weight: 0.08 g (typ.)

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20070701-EN GENERAL

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